

Semiconductor devices — Mechanical and climatic test methods —

Part 33: Accelerated moisture resistance — Unbiased autoclave

The European Standard EN 60749-33:2004 has the status of a
British Standard

ICS 31.080

National foreword

This British Standard is the official English language version of EN 60749-33:2004. It is identical with IEC 60749-33:2004.

The UK participation in its preparation was entrusted by Technical Committee EPL/47, Semiconductors, to Subcommittee EPL/47/1, Film and hybrid integrated circuits, which has the responsibility to:

- aid enquirers to understand the text;
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- monitor related international and European developments and promulgate them in the UK.

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